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Try our New Full-text Search Prototype **GO**[Help](#)

1) Enter a single keyword, phrase, or Boolean expression.  
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)

2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

3) Limit the results by selecting Search Options.

4) Click Search. See [Search Examples](#)

test and "semiconductor  
memory" and "same logic state"

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

## Search Options:

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